

Instabilities simulation and observation

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Y. Suetsugu, S. Terui, M. Tobiyama, D. Zhou

21-th KEKB Accelerator Review Committee

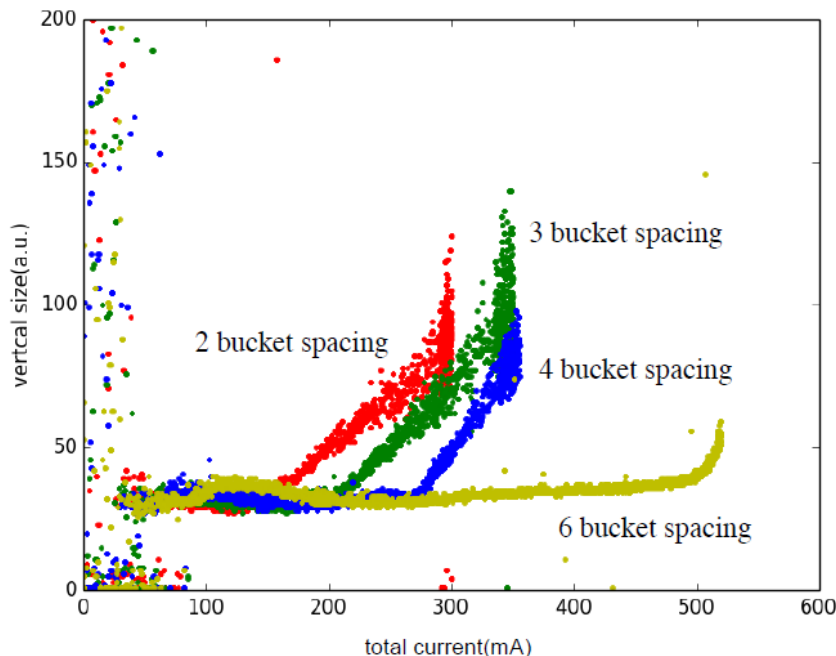
KEK, 13-15 June, 2016

Contents

- Beam size blow-up due to Electron cloud
- Coupled bunch instability due to electron cloud
- Coupled bunch instability in HER
- Tune shift measurement and transverse impedance
- Bunch length measurement

Beam size blow-up in LER

- Beam-size blowup observed in KEKB has been seen in early stage of SuperKEKB commissioning
1. Threshold $I \sim 300\text{mA}$ in Apr 19 (Y. Funakoshi)
 2. Electron cloud has been monitored at AL chamber w and w/o TiN coating (Y. Suetsugu).
 3. Beast study threshold $I \sim 600\text{mA}$, $N_{\text{bunch}} = 1576$ in May 17 (Nakayama et al)
 4. Systematic study in 1 June (H. Fukuma et al.)
 5. Permanent magnets are set at aluminum bellows.(Y. Suetsugu et al.)
 6. Systematic studies in 8 July (H. Fukuma et al.)



June 1, 2016

4 train x150 bunches, $N_{\text{bunch}} = 600$

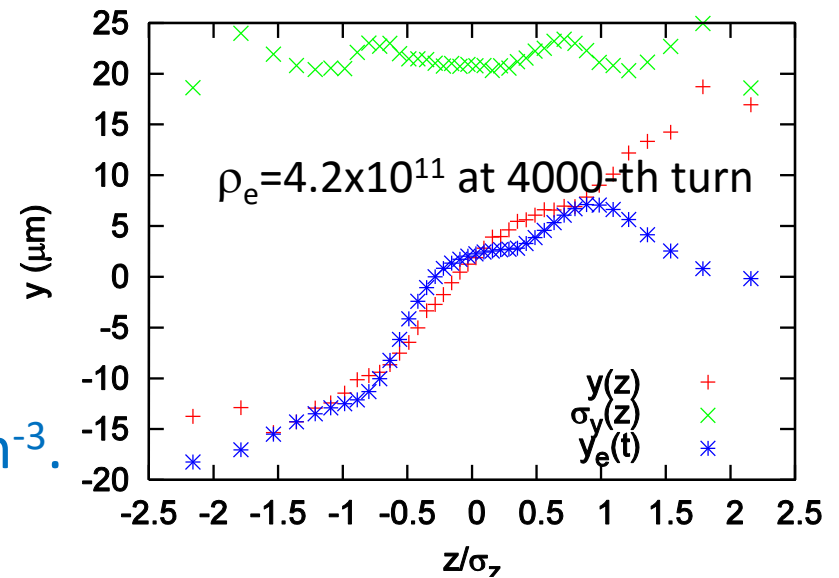
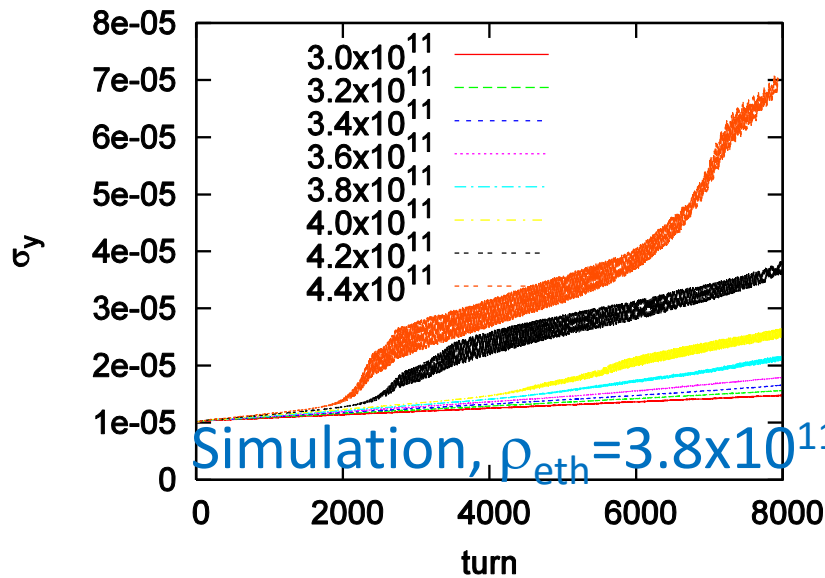
Threshold beam current

160, 200, 260, 500 mA for 2, 3, 4,
6 bucket spacing

H. Fukuma et al.,

Instability simulation at SuperKEKB design stage

- Using code PEHTS



$$\rho_{e,th} = \frac{2\gamma\nu_s\omega_e\sigma_z/c}{\sqrt{3}KQr_e\beta_yL} = 2.2 \times 10^{11} \text{ m}^{-3},$$

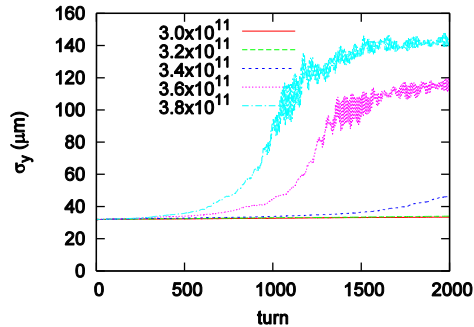
where $K = \omega_e\sigma_z/c = 17$ and $Q = \min(\omega_e\sigma_z/c, 10)$

Design target for vacuum system: $\rho_e < 10^{11} \text{ m}^{-3}$ in average of whole ring

Simulation studies using beam study condition

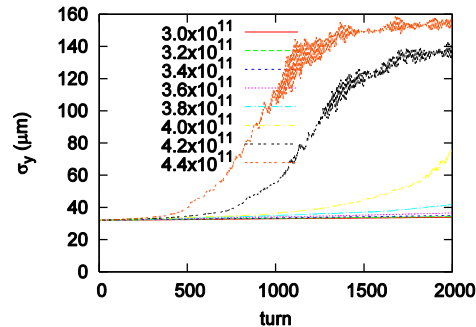
Threshold of the electron density

$$\varepsilon_x=2\text{nm}, \varepsilon_y=15\text{pm}, \sigma_z=6\text{mm}, v_s=0.019$$



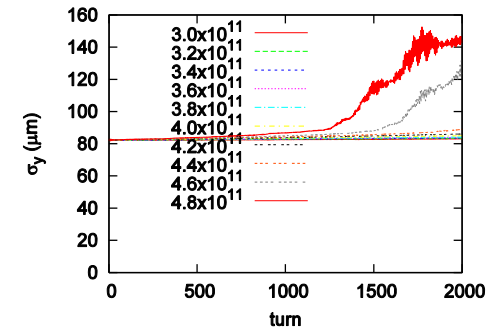
$$N_p=1.6 \times 10^{10}$$

$$I_{th}=160\text{mA}, 4\text{ns spacing}$$



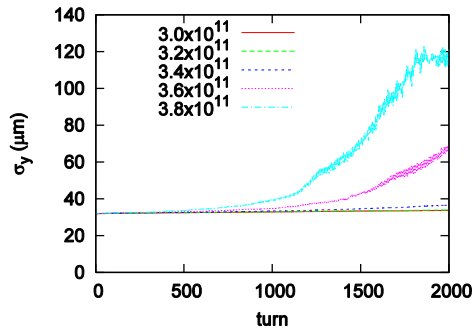
$$N_p=2.7 \times 10^{10}$$

$$I_{th}=260\text{mA}, 8\text{ns spacing}$$



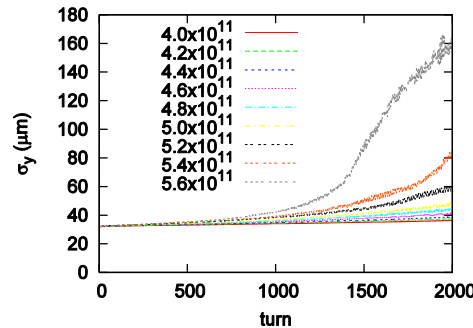
$$N_p=2.1 \times 10^{10},$$

$$\varepsilon_y=100\text{pm}$$



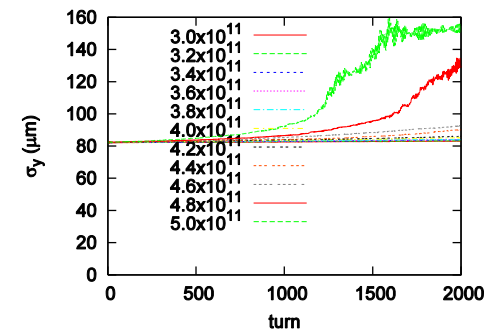
$$N_p=2.1 \times 10^{10}$$

$$I_{th}=200\text{mA}, 6\text{ns spacing}$$



$$N_p=5.2 \times 10^{10}$$

$$I_{th}=500\text{mA}, 8\text{ns spacing}$$



$$N_p=2.4 \times 10^{10},$$

$$\varepsilon_y=100\text{pm}$$

Simulated threshold electron density (condition before solenoid installation)

- $N_b=600$, $\varepsilon_x=2\text{nm}$, $\varepsilon_y=15\text{pm}$, $\sigma_z=6\text{mm}$, $v_s=0.019$

spacing	$I_{p,th}$ (mA)	$N_{p,th}$ (10^{10})	$\omega_e/2\pi$ (GHz)	$\omega_e\sigma_z/c$	$\rho_{eth} (Q=10)$ (10^{11}m^{-3})	$\rho_{eth} (Q=6)$ (10^{11}m^{-3})	$\rho_{eth} (\text{Simu})$ (10^{11}m^{-3})
2 (4ns)	160	1.6	61	7.7	1.91	2.45	3.4
3 (6ns)	200	2.1	71	8.9	1.65	2.45	3.4
4 (8ns)	260	2.7	80	10.1	1.47	2.45	3.8
6 (12ns)	500	5.2	111	14.0	1.47	2.45	5.0
3.06	500	2.0	37	5.5	2.89	2.90	4.4
3.06	600	2.4	41	6.0	2.63	2.65	4.4

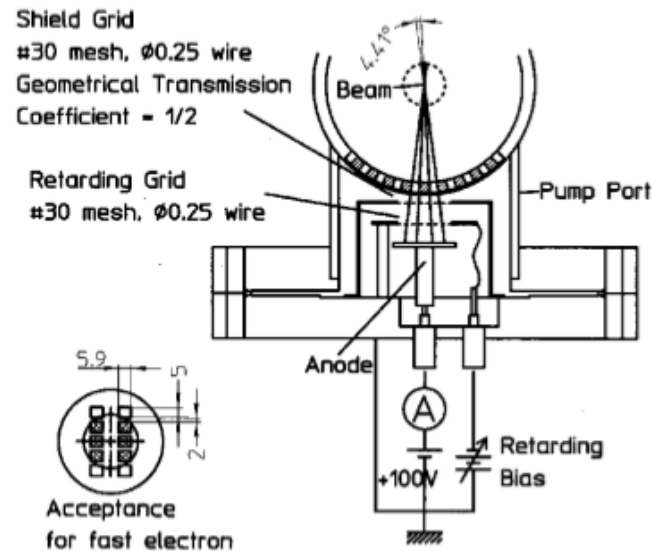
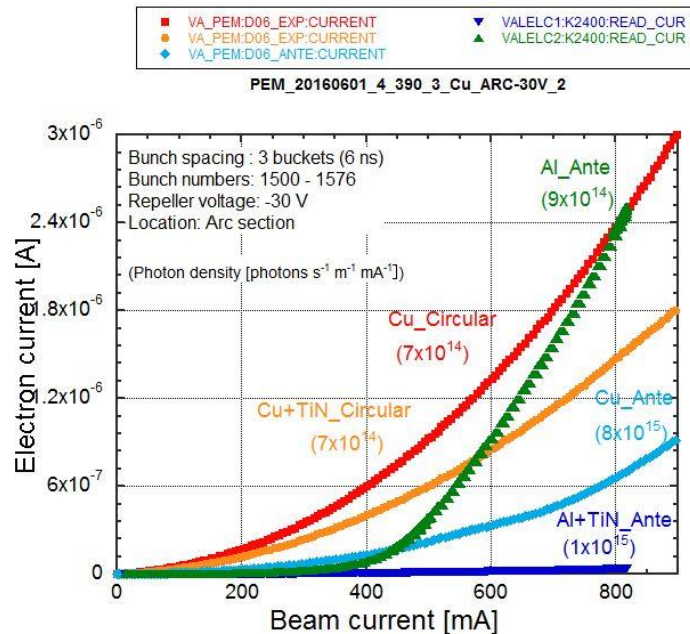
$N_b=1576$,
 $\varepsilon_y=100\text{pm}$

$$\rho_{e,th} = \frac{2\gamma\nu_s\omega_e\sigma_z/c}{\sqrt{3}KQr_0\beta L}$$

$$K = \omega_e\sigma_z/c$$

$$Q = \min(\omega_e\sigma_z/c, 6)$$

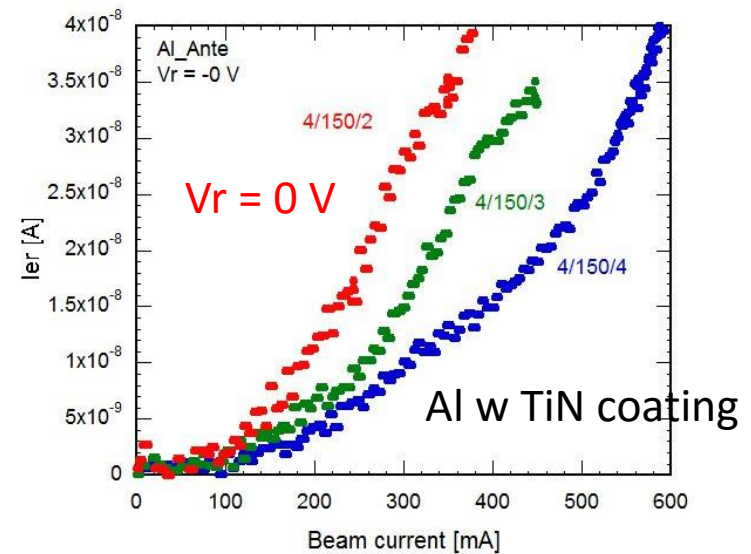
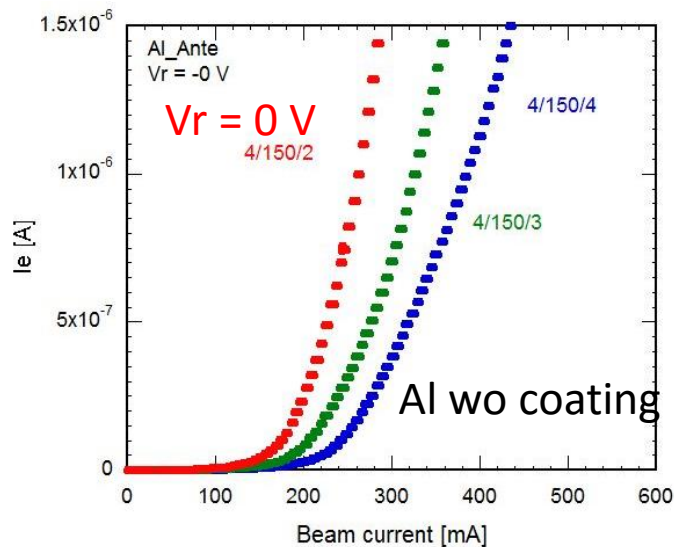
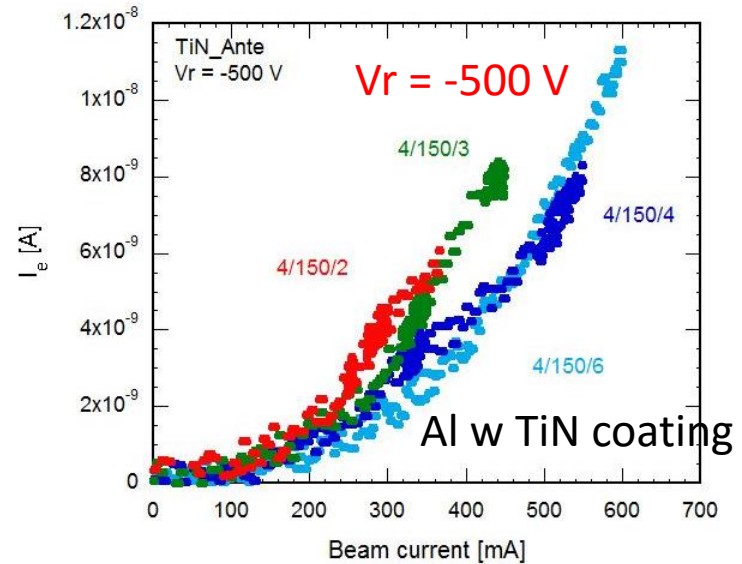
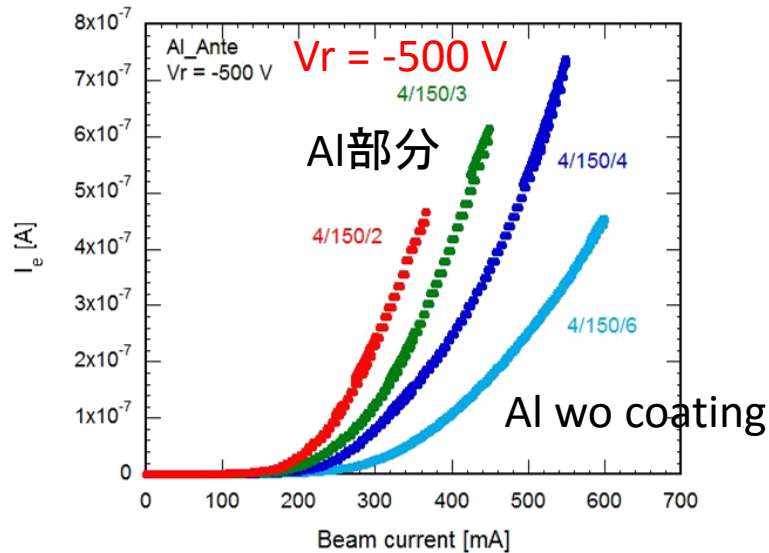
Electron cloud measurement



- Retarding bias, $V=500\text{V}$ or 0V , select electrons with $E>500\text{eV}$ or all, respectively.
- Electron $E=500\text{eV}$, $v=1.3 \times 10^7 \text{ m/s}$. $R/v=3.8\text{ns}$, $R=5\text{cm}$, density can be estimated considering volume with energy gain 500eV from a bunch. 500eV may be critical for 2 (4ns) spacing.
- For $V=0\text{V}$, electron rate production including secondary is detected.

Measured electron current

Y. Suetsugu

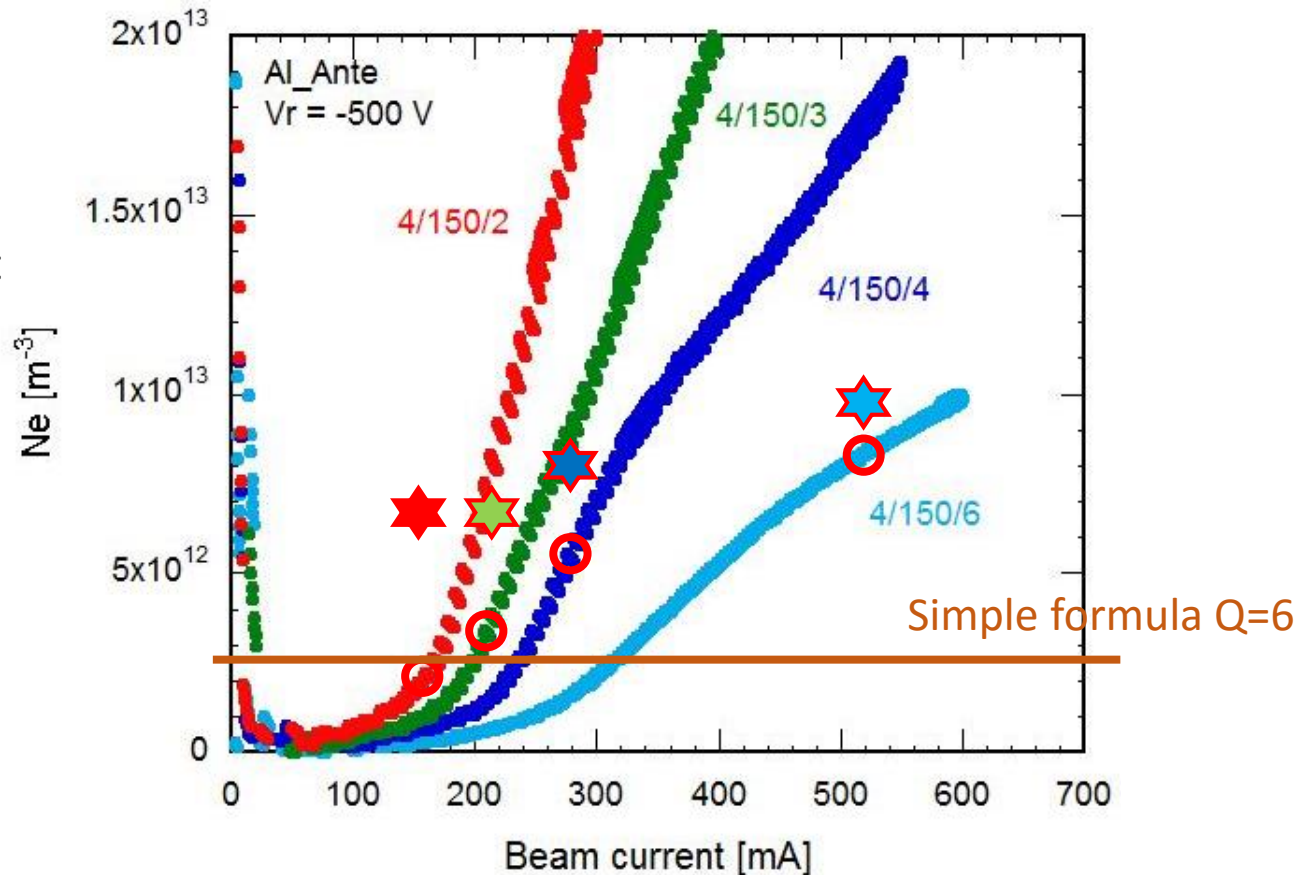


For $V=0V$, $1\mu A$, electron production rate is $0.3 \times 10^9 \text{ m}^{-1}/\text{bunch}$

Electron density at the blow-up threshold

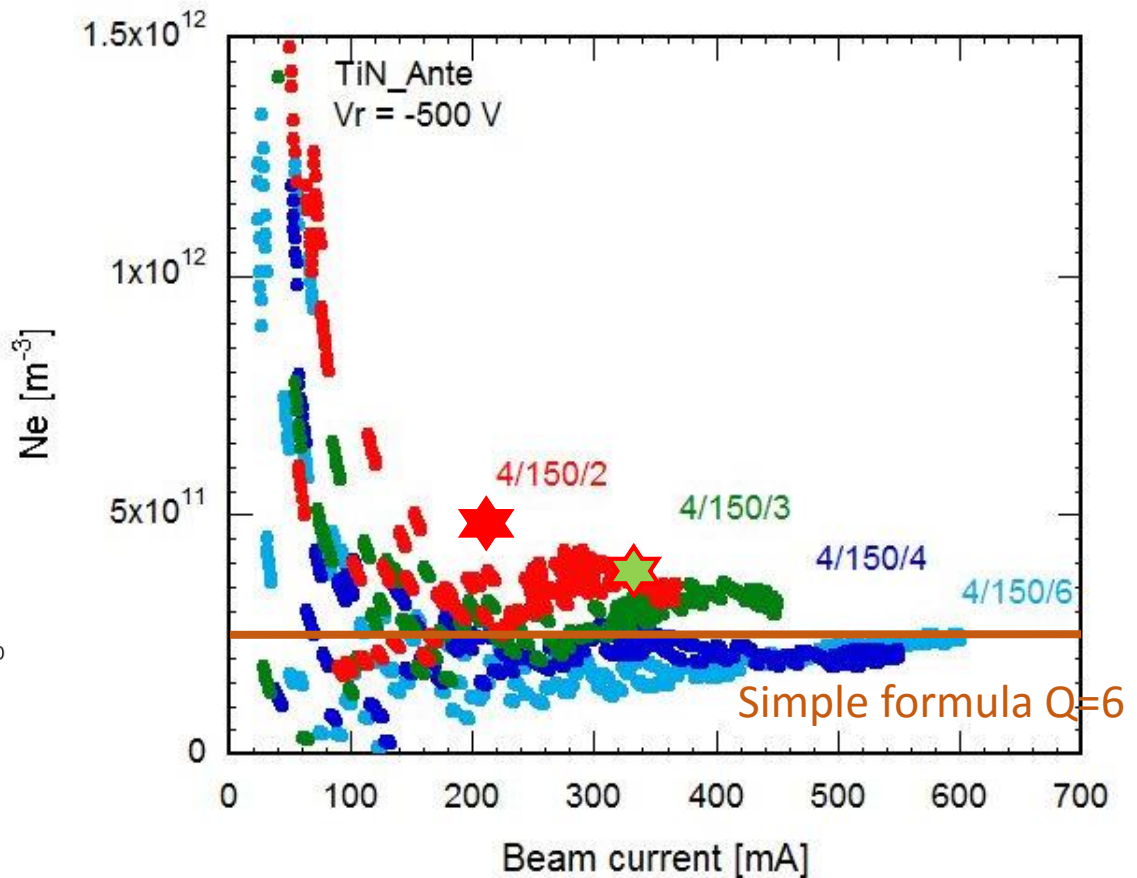
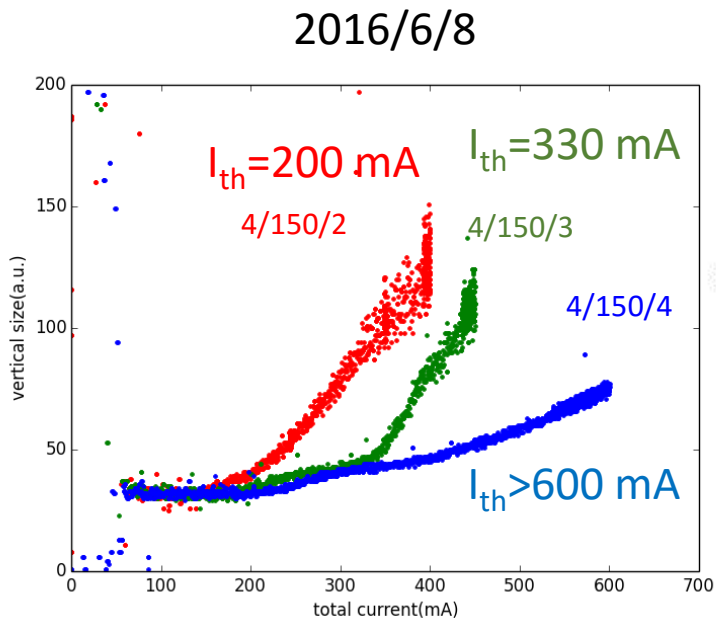
- ☆ Simulated electron density at the threshold current
- Measured threshold current and density

Only Al part



After installation of permanent solenoid at Al bellows

★ Simulated electron density at the threshold current

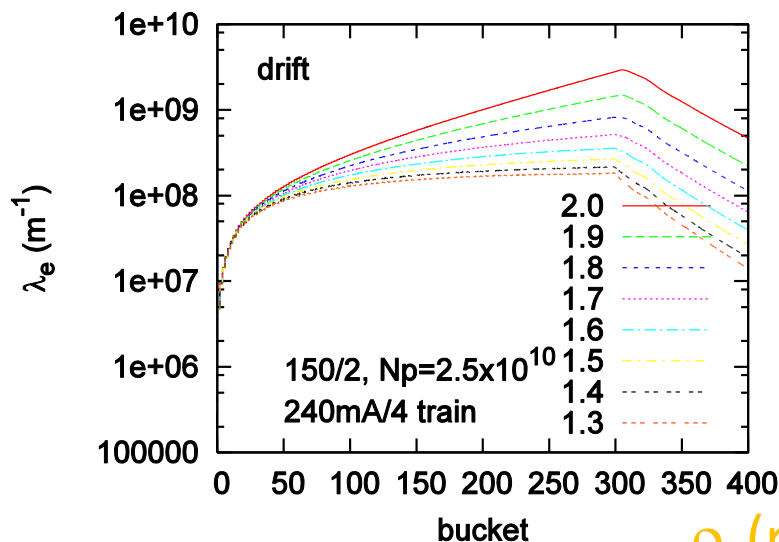


Threshold of electron cloud density after solenoid attach

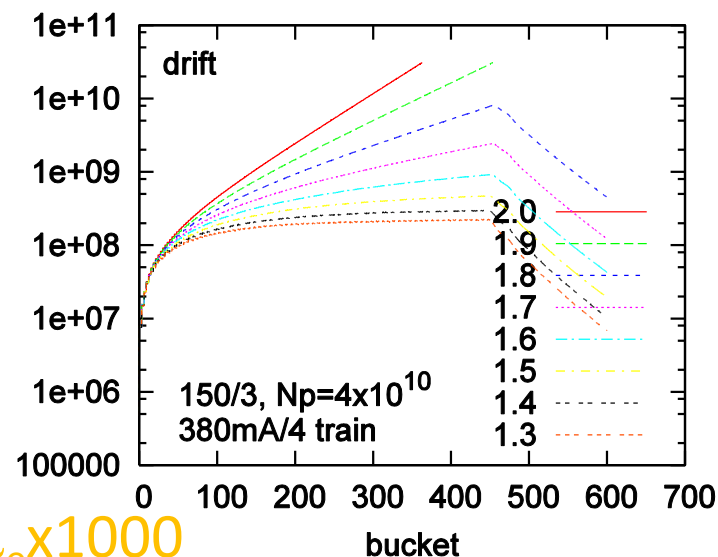
spacing	$I_{p,th}$ (mA)	$N_{p,th}$ (10^{10})	$\omega_e/2\pi$ (GHz)	$\omega_e\sigma_z/c$	$\rho_{eth} (Q=10)$ ($10^{11}m^{-3}$)	$\rho_{eth} (Q=6)$ ($10^{11}m^{-3}$)	$\rho_{eth} (Simu)$ ($10^{11}m^{-3}$)
2 (4ns)	200	2.1	71	8.9	1.65	2.45	3.4
3 (6ns)	330	3.5	91	11.5		2.45	4.8
4 (8ns)	>600	>6.3					
6 (12ns)							
3.06	500	2.0	37	5.5	2.89	2.90	4.4
3.06	600	2.4	41	6.0	2.63	2.65	4.4

Simulated electron cloud build up in Drift

$N_p=2.5 \times 10^{10}$, $I=240$ mA for $N_b=150 \times 4=600$

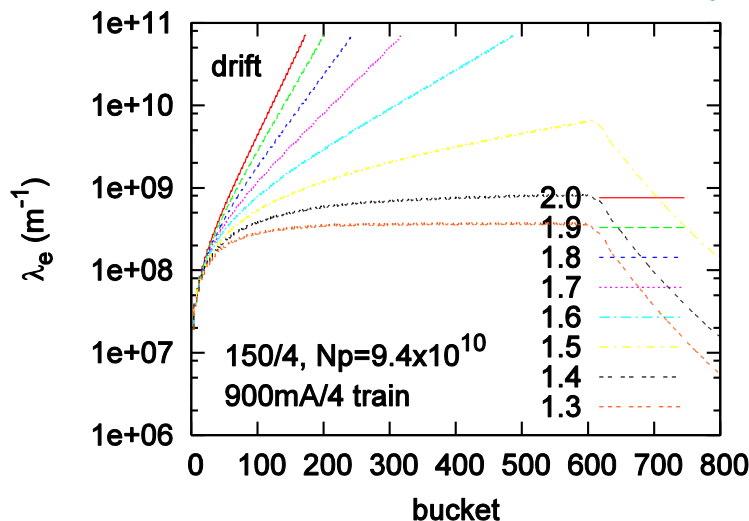


$N_p=4 \times 10^{10}$, $I=380$ mA for $N_b=600$

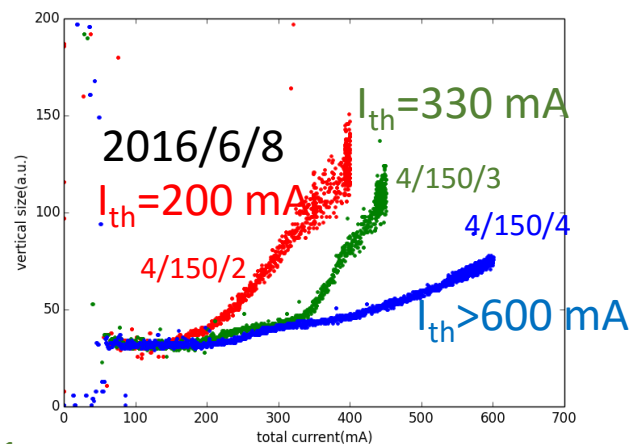


$$\rho_e(r=0) \sim \lambda_e \times 1000$$

$N_p=9.4 \times 10^{10}$, $I=900$ mA for $N_b=600$



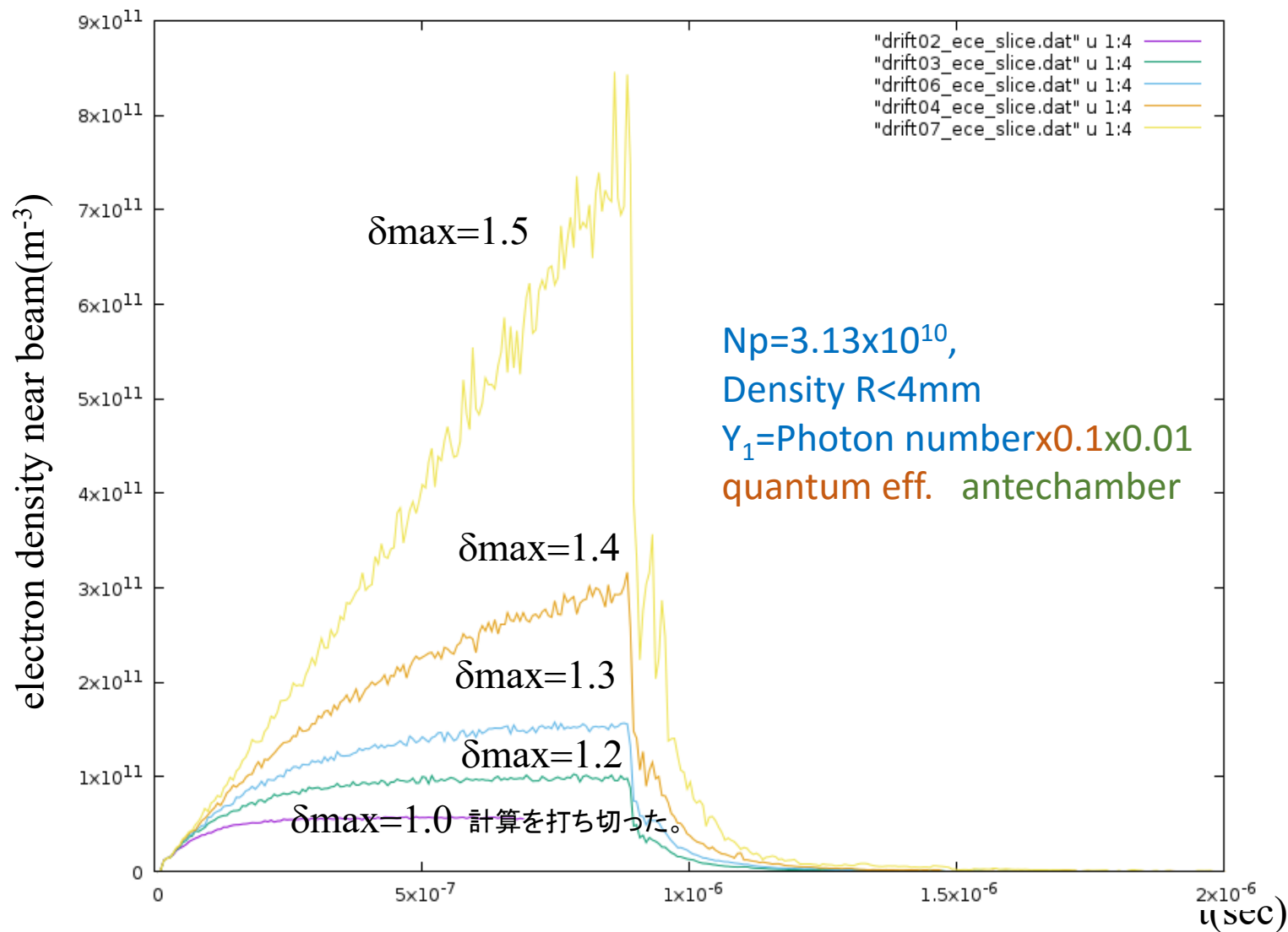
Beam current: Slightly higher than measured threshold



$$Y_1 = \text{Photon number} \times 0.1 \times 0.01$$

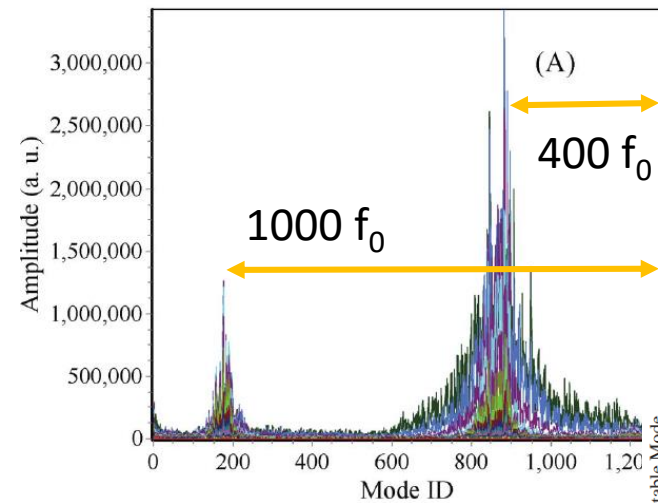
E cloud buildup

CLOUDLAND, Fukuma

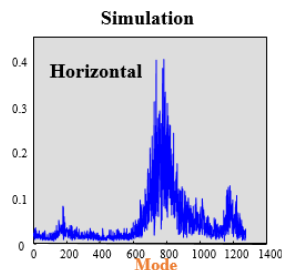
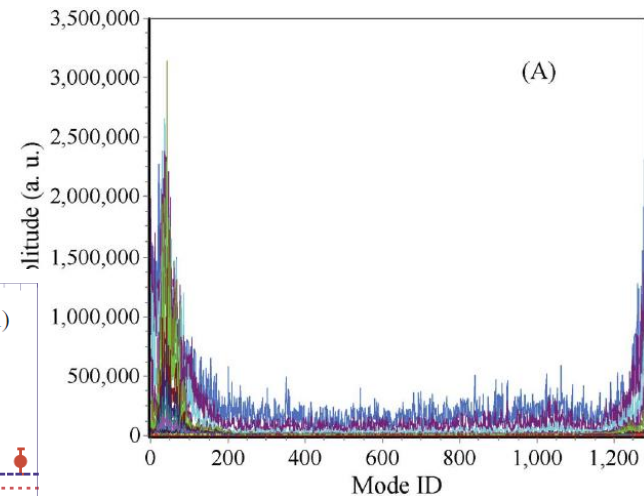
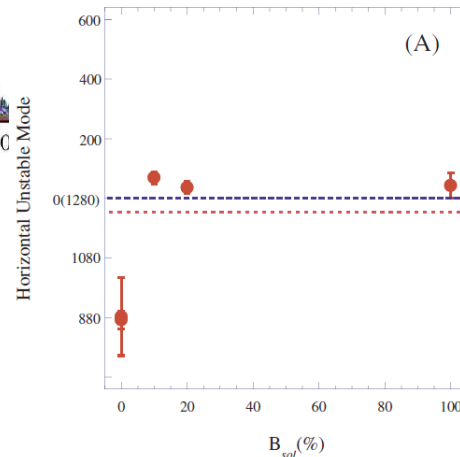


Coupled bunch instability caused by electron cloud

- Electron cloud motion reflects coupled bunch instability mode.
- Electrons in drift, short range wake $\sim 10\text{ns}$
- Electrons in solenoid, slow rotation around chamber surface.



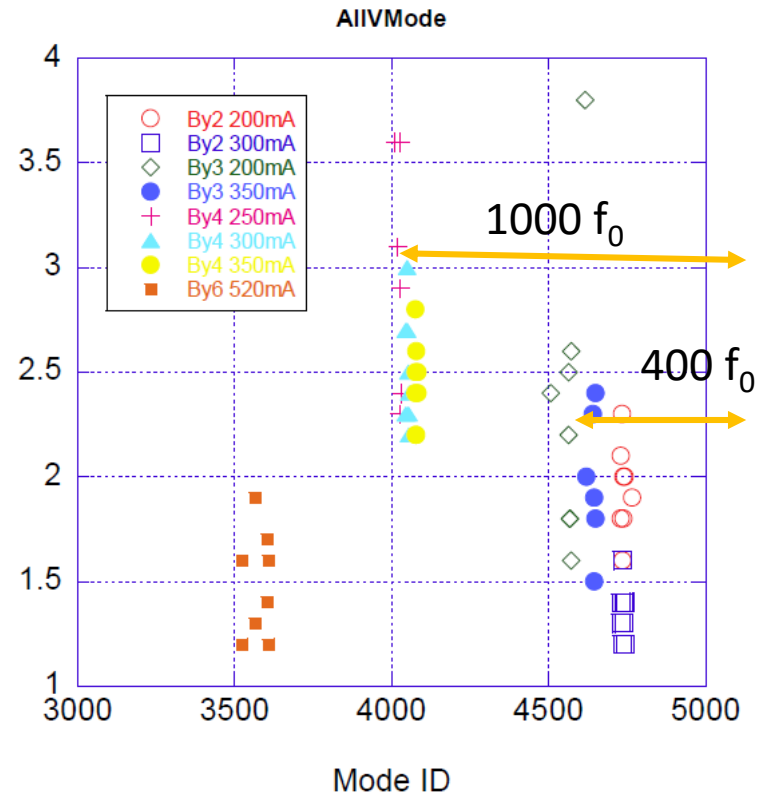
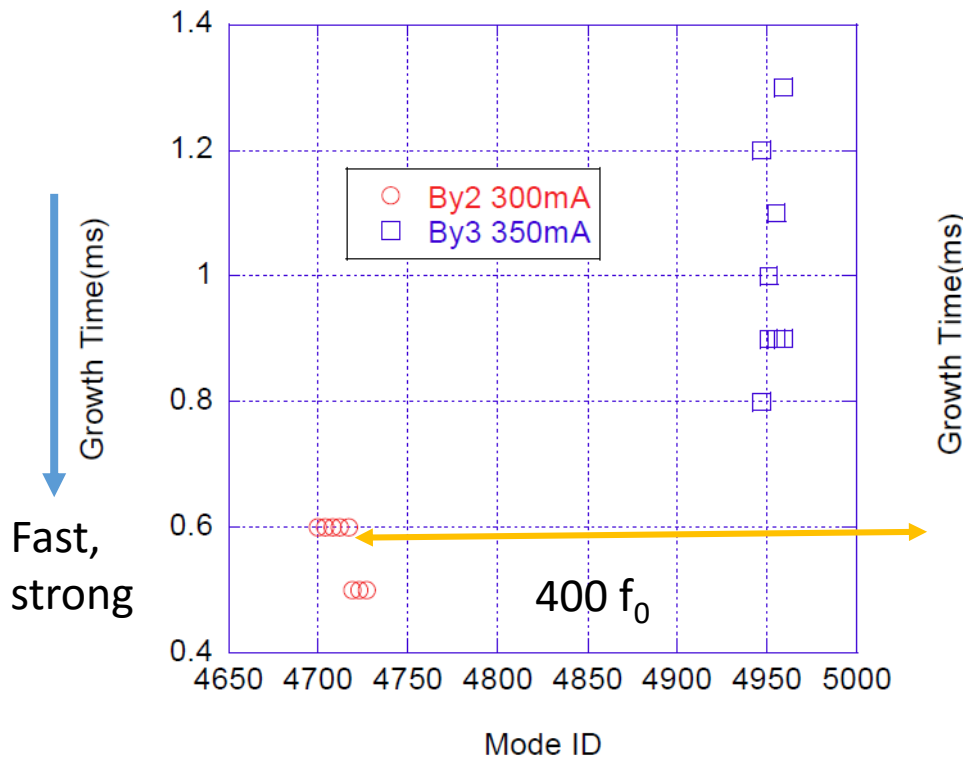
KEKB



Unstable mode (before solenoid installation)

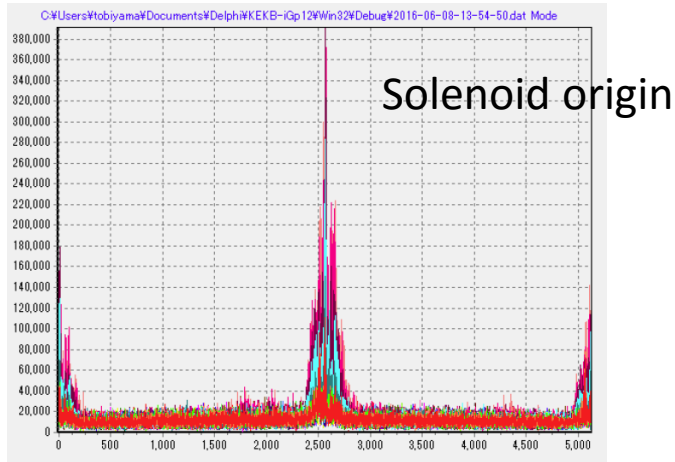
M. Tobiyama

- Typical signal of coupled bunch instability caused by drift electrons

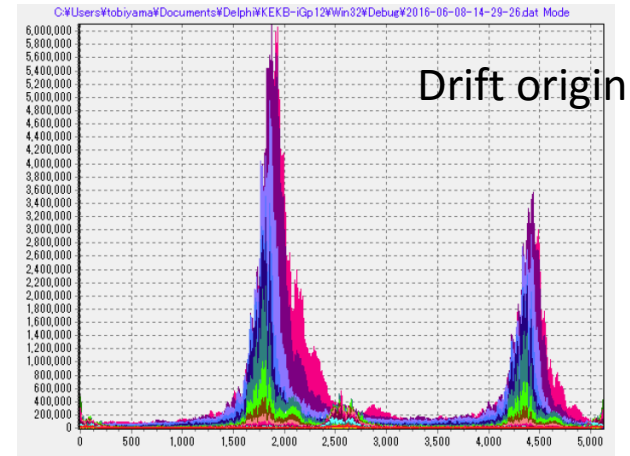


Mode spectrum

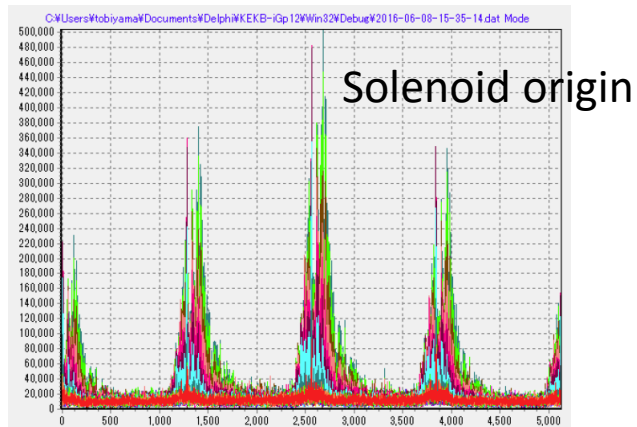
By 2 ver 300mA



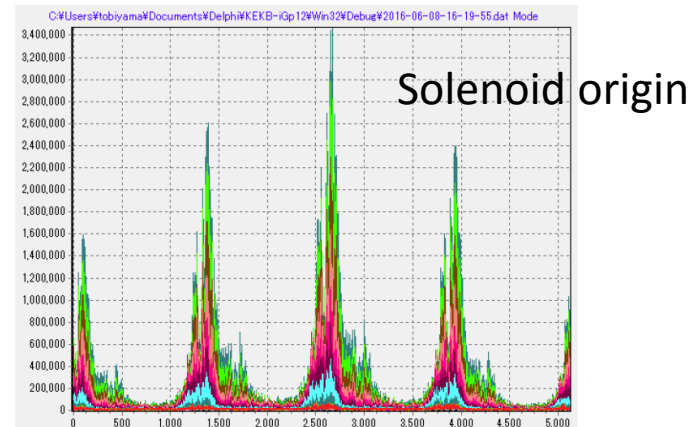
400mA



By 4 ver 350mA

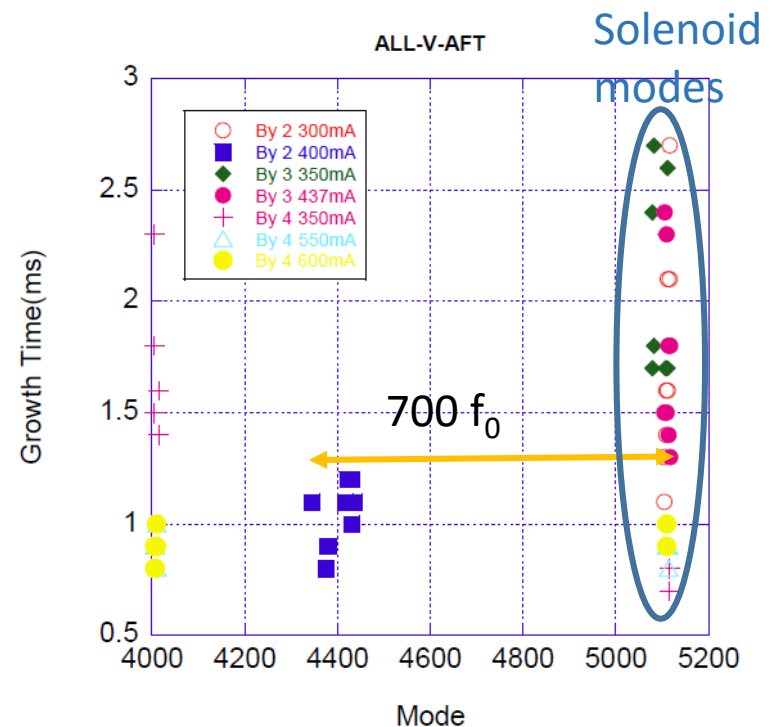
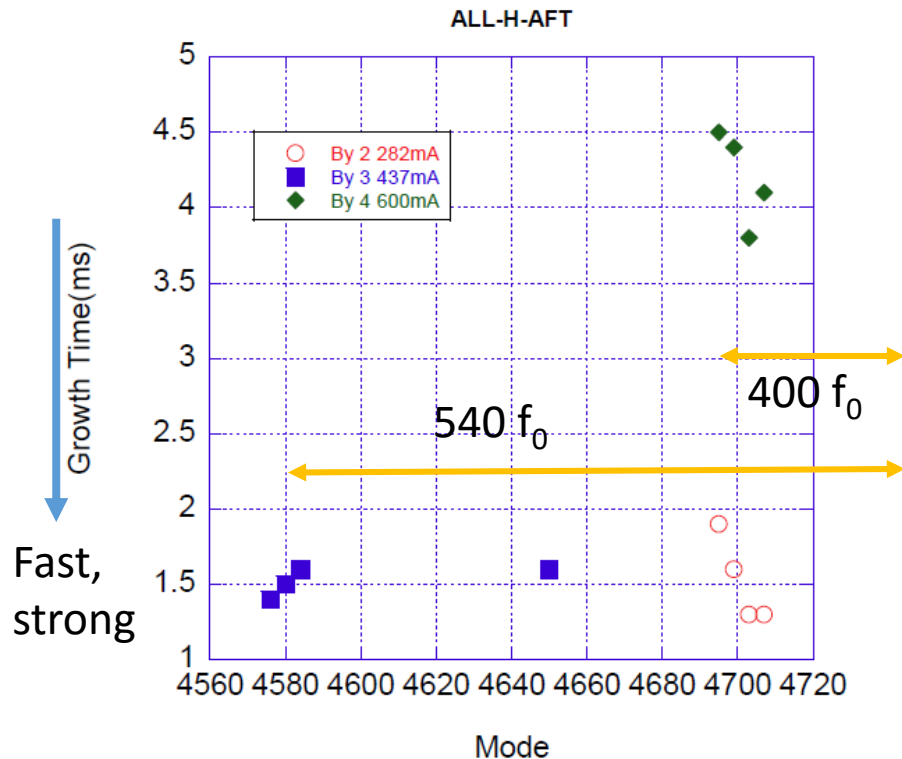


600mA



Unstable mode (after solenoid installation)

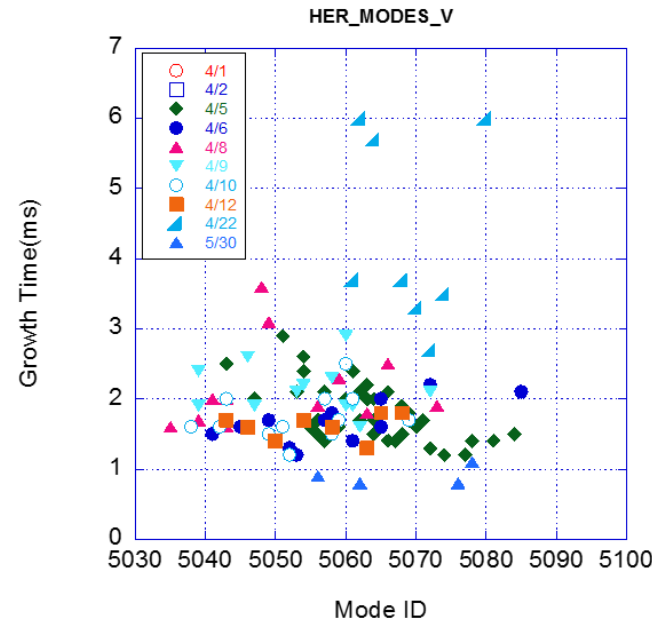
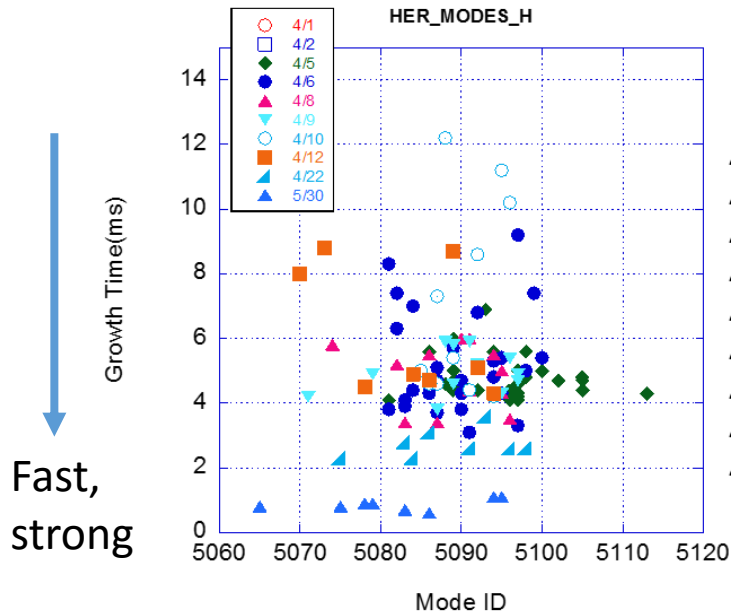
- Typical mode caused by electrons in solenoid is seen.
- Mode seems to change to those of drift origin at high current.



Coupled bunch instability in electron ring (HER)

M. Tobiyama

• Ion?



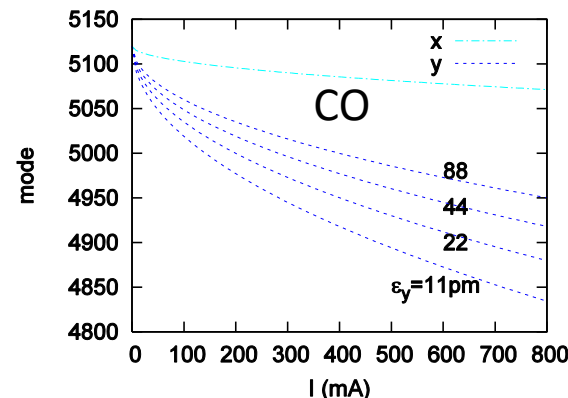
Beam current Nb		
Apr.1	174mA	1163
Apr.2	174	1163
Apr.5	225	953
Apr.6	240	953
Apr.8	280	953
Apr.9	280	1163
Apr.10	280	1163
Apr.12	340	1163
Apr.22	520	1394
May.30	738	1576

$$\omega_{i,x}^2 = \frac{2\lambda_e r_A c^2}{A_i \Sigma_x (\Sigma_x + \Sigma_y)}$$

$$\omega_{i,y}^2 = \frac{2\lambda_e r_A c^2}{A_i \Sigma_y (\Sigma_x + \Sigma_y)}$$

$$\Sigma_{x(y)} = \sqrt{\sigma_{e,x(y)}^2 + \sigma_{i,x(y)}^2}$$

$$Mode = 5120 - \frac{\omega_{i,xy}}{\omega_0}$$



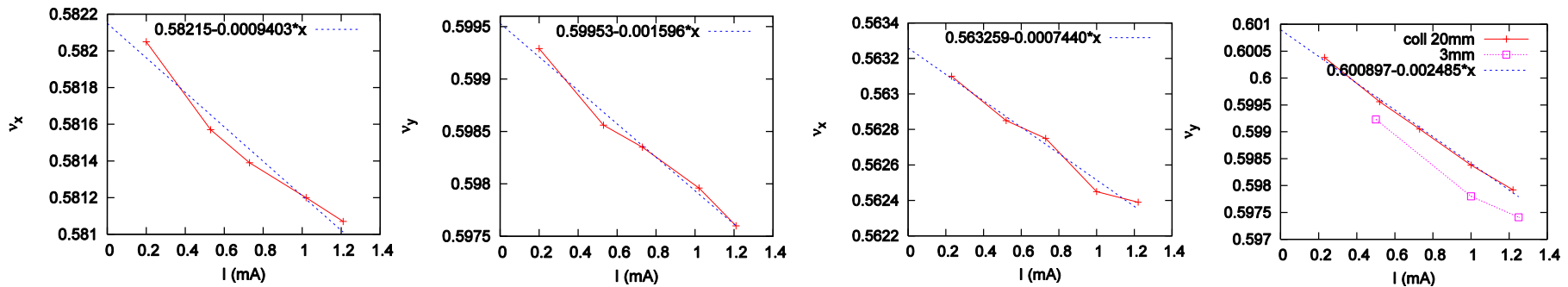
Resistive wall
5120-1=5119

Impedance estimation- transverse

- Tune shift as function of bunch current

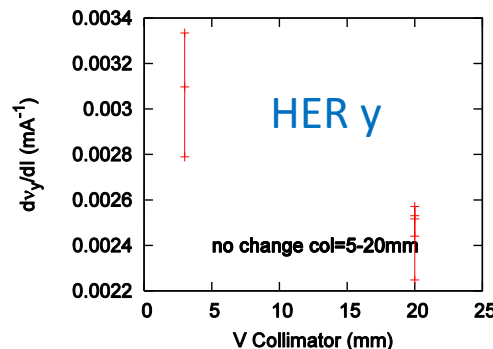
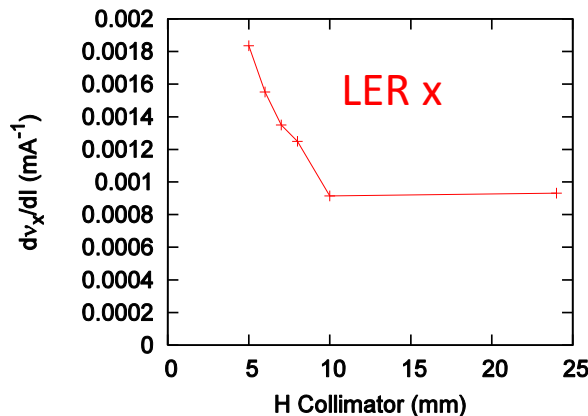
$$\Delta\nu_x = \frac{1}{4\pi^{3/2}} \frac{Nr_e}{\gamma} \frac{L}{v_x \sigma_z} \frac{iZ_{eff}}{Z_0}$$

$$iZ_{eff}(k\Omega) = 33.3 \frac{\Delta\nu_x}{I(mA)} \text{ LER} = 58.2 \frac{\Delta\nu_x}{I(mA)} \text{ HER}$$



$$iZ_{eff} = 31 (x) \quad 53 (y) \text{ k}\Omega/m$$

$$iZ_{eff} = 43 (x) \quad 145 (y) \text{ k}\Omega/m$$

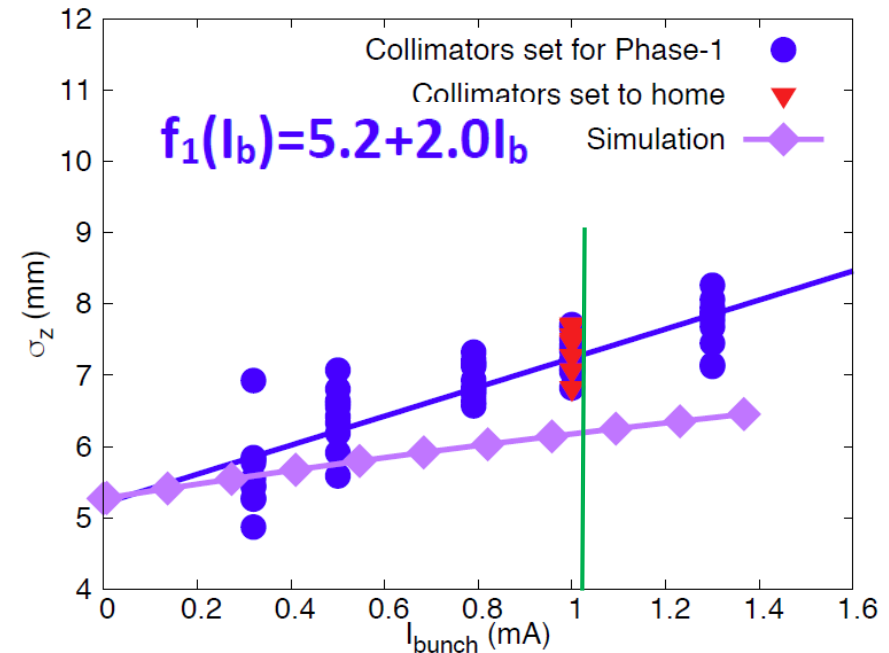
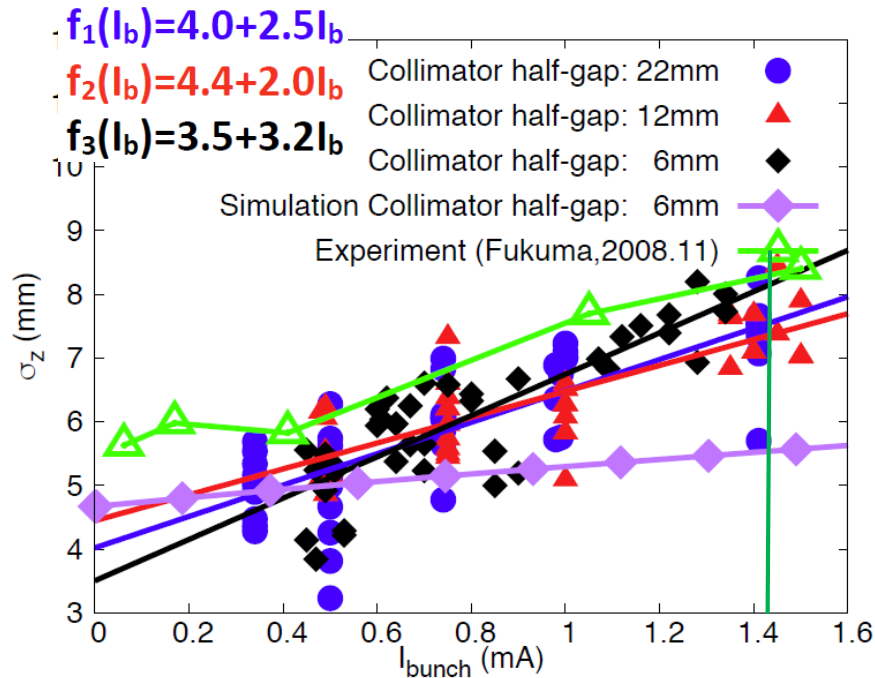


Collimator dependence

$$\text{KEKB-LER: } -0.0034 \text{ mA}^{-1}, 81 \text{ k}\Omega/m$$

$$\text{coll. open } 33\text{-}46 \text{ k}\Omega/m \quad \text{T. Ieiri, EPAC00}$$

Longitudinal impedance issue- Bunch length measurement



Measured by a Streak camera

The behaviors are similar as KEKB for both of LER and HER.
Bunch lengthening is stronger than that of simulation.

Summary

- Beam size blow-up has been observed since early stage of SuperKEKB commissioning.
- Electron density at Al bellows part (5% of circumf.) is high ($\rho_e > 10^{12} \text{m}^{-3}$). Simulations show the electrons can cause fast head-tail instability.
- Coupled bunch instability caused by electron cloud has also been observed as is predicted.
- Installation of Permanent solenoid reduced the blow up. It is possible to operate with 1A, 4 bucket spacing at present condition.
- Tune shift as function of bunch current was measured to estimate transverse impedance. It was 30-50k Ω /m, similar as KEKB.
- Bunch length was measured by a streak camera. Bunch lengthening, which was similar as KEKB, was observed, 7-8 mm at the design current, while no bunch lengthening in prediction.

Thank you for your attention

Rough estimation of Electron density

- Electron current, $I_e = 1\mu\text{A}$.
- Acceptance of the electron detector, $S_{\text{mon}} = 1\text{ cm}^2$.
- Number of electron absorbed (=produced) at chamber wall, $d = 10\text{cm}$.

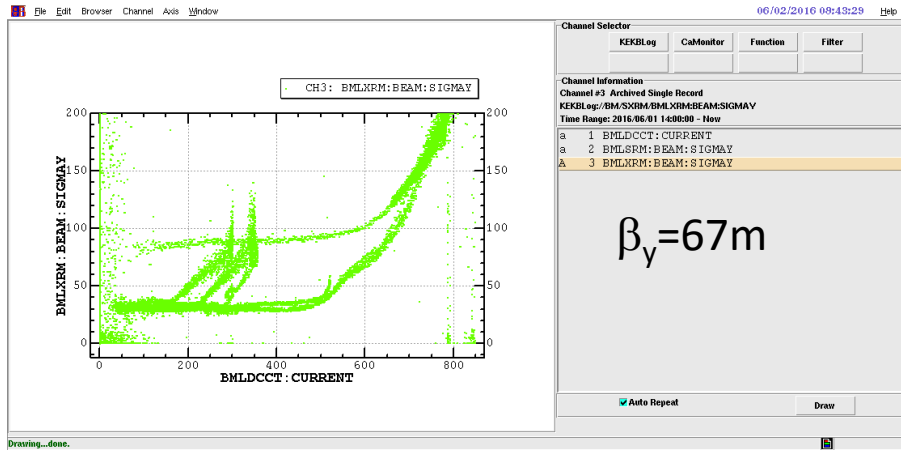
$$n_e = \frac{10^{-6} \times 0.1\pi}{1.6 \times 10^{-19} \times 10^{-4}} = 2 \times 10^{16} \text{ m}^{-3} \text{ s}^{-1}$$

- Electron stay time in the chamber, $\tau_e = 100\text{ns}$. Electron density

$$\rho_e = \frac{2 \times 10^{16} \times 10^{-7}}{0.05^2 \pi} = 2.5 \times 10^{11} \text{ m}^{-3}$$

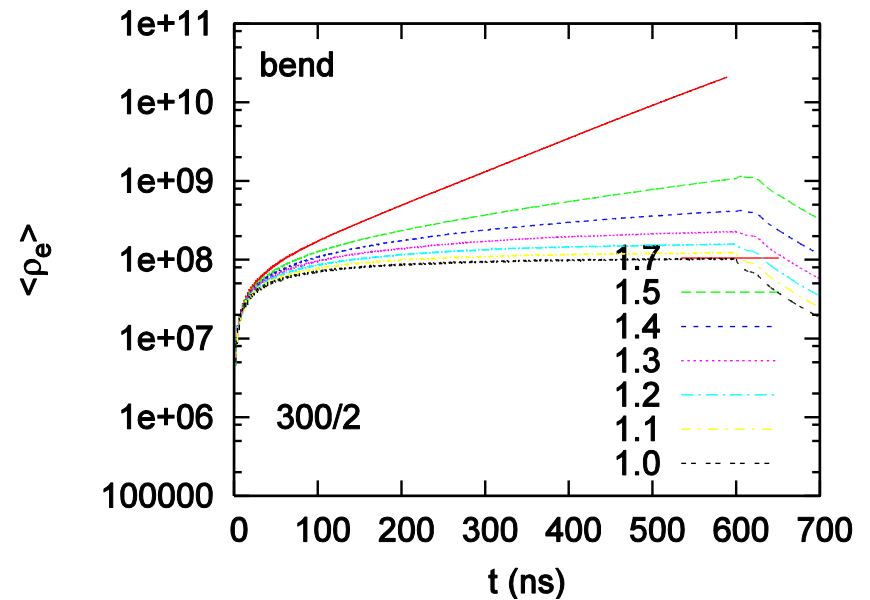
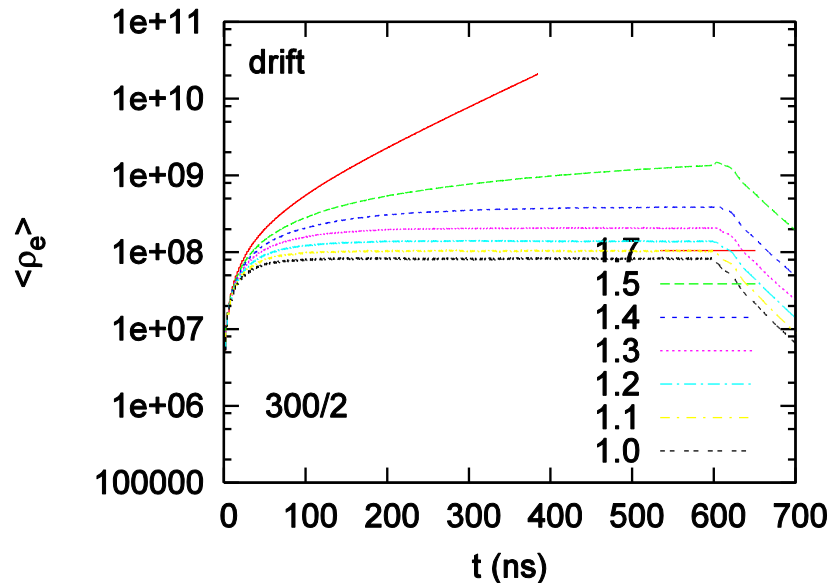
Emittance dependence

- Vertical emittance knob



Design current & spacing

$N_p=9.4 \times 10^{10}$, $I=3600$ mA



金澤氏の式を使った電子密度の算出*

* PAC2005, p.1054

$$D = \frac{\mu(V_b)}{V_{obs}(V_b)} \quad \mu(V_b) = \frac{I_{obs}(V_b)}{en_b f_{rev}} \quad V_{obs}(V_b) = A\pi r_e^2 N_b^2 \frac{m_e c^2}{eV_b}$$

$$e = 1.602\text{E-}19 \text{ [C]}$$

$$f_{rev} = 1\text{E}5 \text{ [s}^{-1}\text{]}$$

$$r_e = 2.818\text{E-}15 \text{ [m]}$$

$$m_e = 9.109\text{E-}31 \text{ [kg]}$$

$$c = 3.0\text{E}8 \text{ [ms}^{-1}\text{]}$$

n_b = バンチ数

πA = 通過確率 = $0.0003 \times 1/4 = 7.5\text{E-}5$

V_b = グリッド電圧 [V]

N_b = バンチ内の e^+ の数

$$N_b = \frac{I}{n_b f_{rev} e} \quad I = \text{ビーム電流 [A]}$$

まとめると、

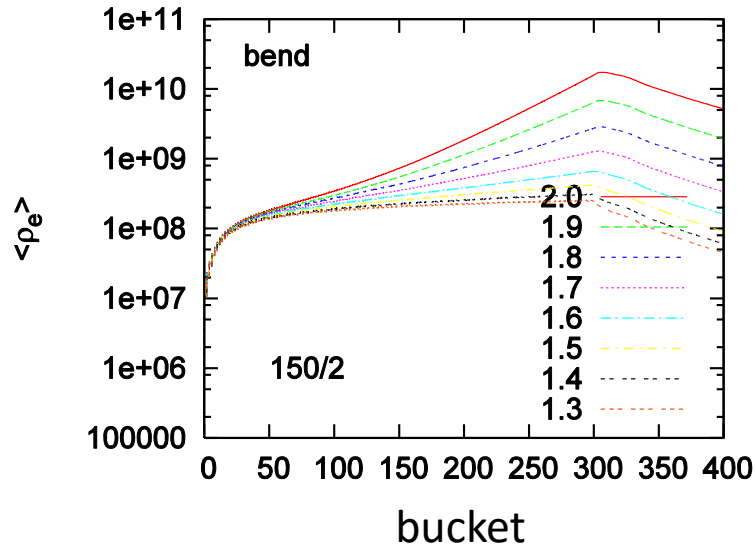
$$D = 2.630\text{E}13 \times \frac{I_{obs} n_b V_b}{I^2}$$

例えば、2/150/3 $V_r = -30 \text{ V}$, $I = 200 \text{ mA}$, $I_{obs} = 1\text{E-}7 \text{ A}$ の場合 (平均で)

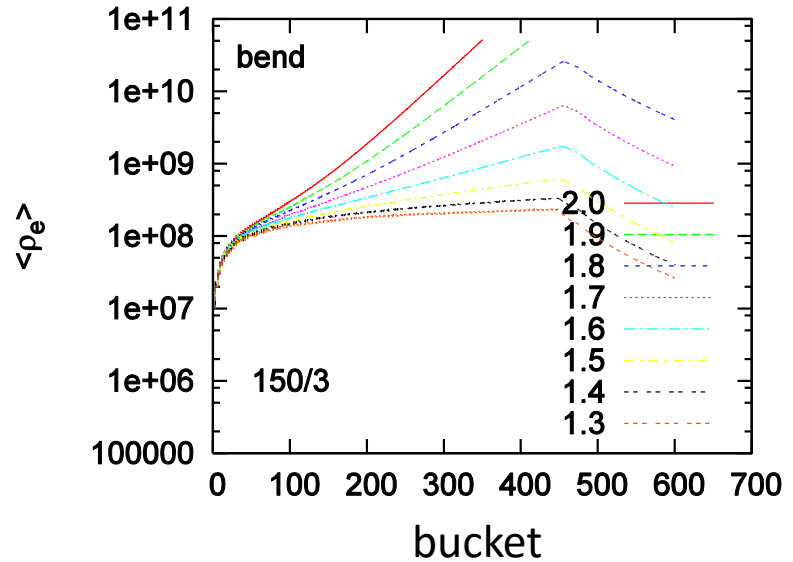
$$n_b = 600, V_b = 30 \quad D = 1.18\text{E}12 \text{ [e}^{-} \text{ m}^{-3}\text{]}$$

Simulated electron cloud build up in Bend

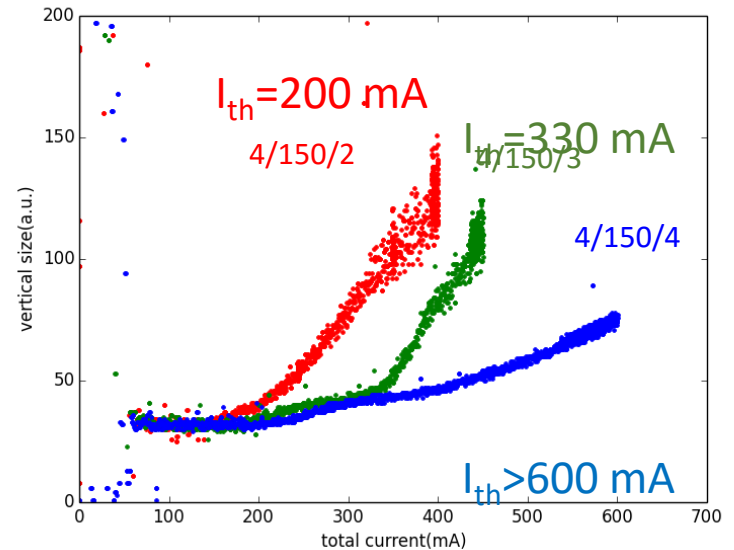
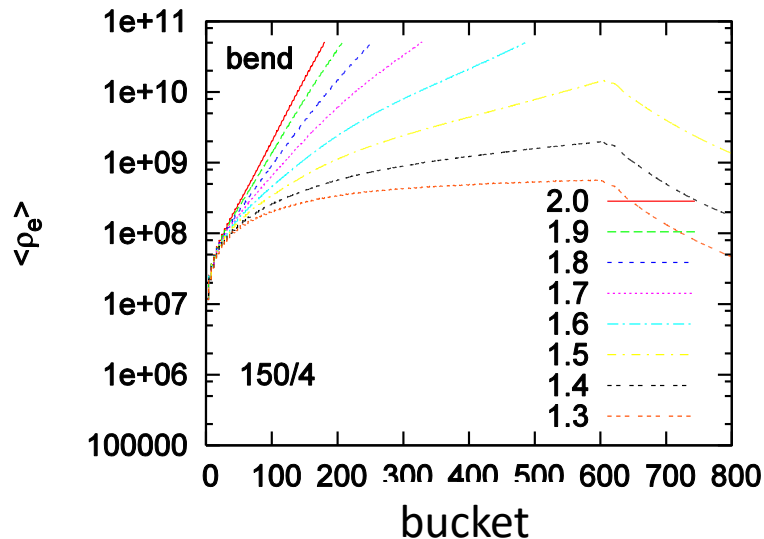
$N_p=2.5 \times 10^{10}$, $I=240$ mA for $N_b=600$



$N_p=4 \times 10^{10}$, $I=380$ mA



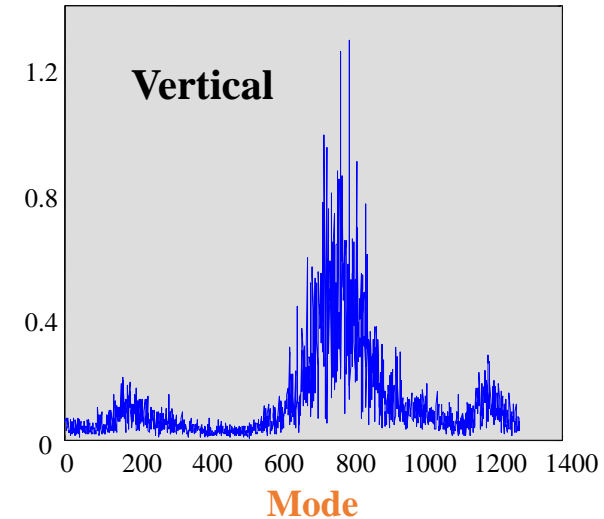
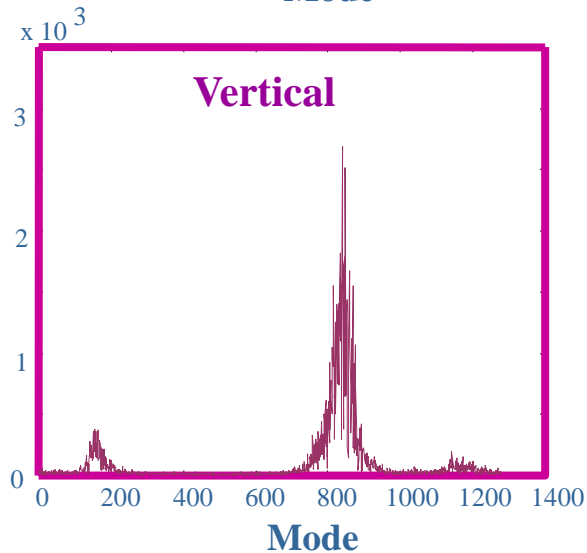
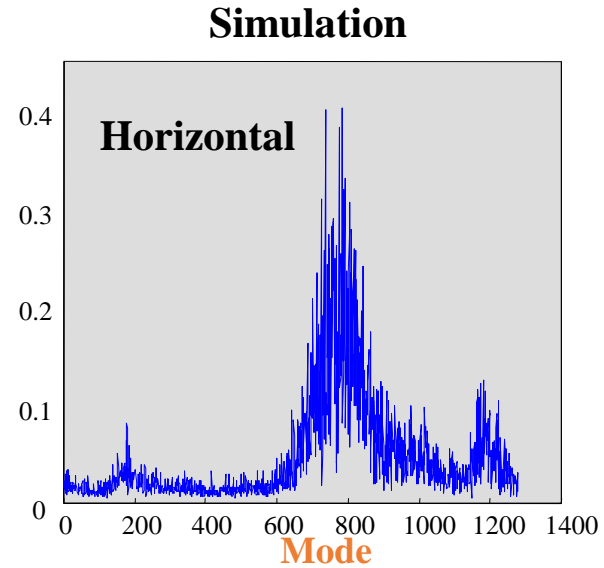
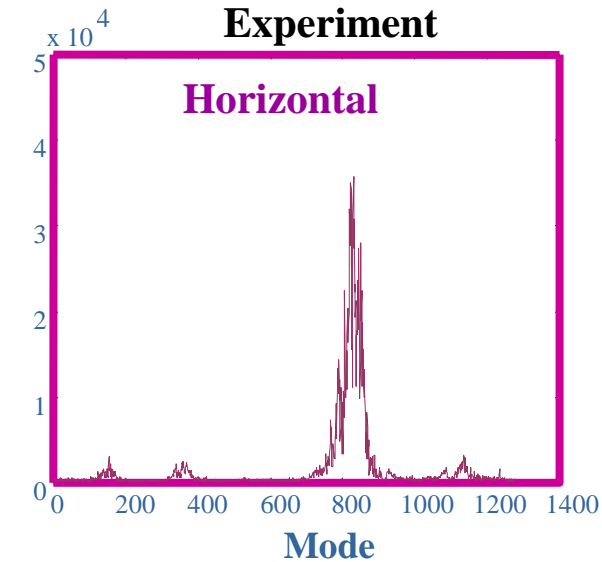
$N_p=9.4 \times 10^{10}$, $I=900$ mA



Multipactoring arises $Y_{2\max} \geq 1.5$ at the threshold beam currents.

KEKB

Solenoid-Off



Su Su Win et al, (EC2002)